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Certificate of Analysis

Revision No.: 001

ISO/IEC

17025:2017

Revision Date: 03/09/2022

ISC

9001:2015

IS0

17034:2016

Certified Reference Material

Product ID: MBH-13X 33425 A

Product Description: Austenitic Stainless Steel

Description and Intended Use: This Certified Reference Material is covered under the scope of accreditation to ISO 17034 by LGC Standards - Manchester, NH. As an ISO 17034 certified reference material, appropriate use of this material will fulfill the certified reference material and traceability requirements for use in ISO 17025 accredited laboratories. This CRM may come in the form of a solid disk, or chips. The intended use of this CRM may include, but is not limited to, the calibration of instruments and the validation of analytical methods.

Certified Values listed in wt.% with associated uncertainties

AI	0.017 ± 0.003	As	0.0021 ± 0.0008	С	0.039 ± 0.001	Co	0.092	± 0.002
Cr	22.3 ± 0.1	Cu	0.204 ± 0.005	Mn	0.997 ± 0.008	Мо	2.52	± 0.02
Ν	0.0106 ± 0.0008	Nb	0.047 ± 0.003	Ni	20.90 ± 0.08	Р	0.028	± 0.002
S	0.0052 ± 0.0008	Sb	0.002 ± 0.003	Si	0.85 ± 0.01	Sn	0.0106	± 0.0008
Ti	0.178 ± 0.003	V	0.014 ± 0.003					

Indicative Values listed in ppm

(<10) R (<2) (<52%) O (<60) Pb (10) (60) Fe W Zr

Homogeneity and Uncertainty: "Uncertainty" values, as reported adjacent to certified concentration values, are based on a 95% Confidence Interval. These estimated uncertainties include the combined effects of method imprecision, material inhomogeneity, and any bias between methods. Homogeneity data from experimental XRF results are reflected in both the overall statistics and certified data. Homogeneity samples are selected by a systematic sampling procedure. The number of samples may be determined by equation 1, where Nprod is the number of units produced and Nmin is the number of samples used for homogeneity testing. These samples are arranged in a simple randomized design such that each sample is analyzed multiple times by XRF. Homogeneity may also be determined within sample using an applied version of ASTM E826. A single factor ANOVA is used to calculated uncertainty due to inhomogeneity (Uhom). Uncertainty of the material is calculated by equation 2, where H=Uhom, S= Standard deviation, t= t-value at 95% CI, and n= number of observations

$$1. N_{MIN} = \max(10, \sqrt[3]{N_{PROD}})$$

$$2.U_{CRM} = \frac{\sqrt{H^2 + S^2}}{\sqrt{n}} * i$$

Certification Laboratories: Much of the analytical work performed to assess this material has been carried out by laboratories with proven competence, as indicated by their accreditation to ISO 17025. It is an implicit requirement for this accreditation that analytical work should be performed with due traceability, via an unbroken chain of comparisons, each with stated uncertainty, to primary standards such as the mole, or to nationally- or internationally-recognised reference materials. Of the individual results herein, some have traceability (to the mole) via primary analytical methods. Some are traceable to substances of known stoichiometry. Most have traceability via commercial solutions. Furthermore, some results have additional traceability to NIST standards, as part of the analytical calibration or process control.

- LGC Standards Manchester, NH
- Connecticut Metallurgical, Inc. East Hartford, CT . .
- Applied Technical Services Marietta, GA EAG Laboratories - Liverpool, NY
- Dirats Laboratories Westfield, MA
- IMR Test Labs Lansing, NY . NSL Analytical Services - Cleveland, OH
- Luvak Inc. Boylston, MA
- Scrooby's Laboratory Service Rynfield, South Africa
- SGS MSi Melrose Park, IL

. RSML - Bengaluru, India

New Hampshire Materials Laboratory - Somersworth, NH

- Instytut Metalurgii Żelaza Gliwice, Poland •
- IMR Test Labs Louisville, KY

Instructions for Use: The test surface is on the opposite side of the labeled surface, which includes the material identification. The entire thickness of the unit is certified. However, the user is cautioned not to measure disks less than 2 mm thick when using X-ray fluorescence spectrometry. Each packaged disk has been prepared by finishing the test surface using a lathe. The user must determine the correct surface preparation procedure for each analytical technique. The user is cautioned to use care when either resurfacing the disk or performing additional polishing, as these processes may contaminate the surface. The minimum sample size for chips should be individually evaluated based on the analytical technique used; this would typically be greater than 0.1 grams. The material should be stored in a cool, dry location when not in use.

Chips are not recommended for gas analysis.

Period of Validity: The certification of this material is valid indefinitely, within the uncertainty specified, provided the material is handled and stored in accordance with the instructions stated on this certificate. The certification is nullified if the material is damaged, contaminated, otherwise modified, or used in a manner for which it was not intended.

Kimberly Halkiotis, Global Product Manager

March 9, 2022 Certification Date



ISO 17034 Accredited: Reference Materials Producer, Certificate # 2848.02 ISO/IEC 17025 Accredited: Chemical Testing, Certificate # 2848.01

Conditions of Sale and Supply: All CRMs & RMs sold are subject to applicable LGC Standard Terms and Conditions of Sale.



The following data represents all pertinent information reported as it applies to the chemical characterization of this material.

	AI	As	В	С	Co	Cr	Cu	Fe	Mn	Мо	Ν	Nb	Ni
1	0.0104	0.0009	0.0002	0.0360	0.0840	21.827	0.1830	51.740	0.9700	2.4700	0.0090	0.0320	20.500
2	0.0120	0.0015	0.0002	0.0360	0.0860	21.940	0.1900	52.000	0.9730	2.4700	0.0100	0.0351	20.600
3	0.0123	0.0017	<0.005	0.0360	0.0863	22.080	0.1920		0.9740	2.4700	0.0102	0.0410	20.670
4	0.0128	0.0020		0.0362	0.0869	22.167	0.1930		0.9760	2.4850	0.0105	0.0410	20.710
5	0.0133	0.0020		0.0370	0.0880	22.190	0.1945		0.9790	2.4900	0.0110	0.0420	20.827
6	0.0133	0.0030		0.0380	0.0890	22.190	0.1950		0.9858	2.4940	0.0110	0.0444	20.830
7	0.0140	0.0036		0.0390	0.0900	22.200	0.1970		0.9910	2.4984	0.0112	0.0468	20.870
8	0.0165	< 0.002		0.0395	0.0900	22.230	0.2000		0.9919	2.5035	0.0120	0.0470	20.870
9	0.0170	< 0.002		0.0400	0.0900	22.270	0.2000		0.9940	2.5100		0.0470	20.870
10	0.0170	<0.005		0.0400	0.0910	22.300	0.2000		0.9980	2.5100		0.0470	20.884
11	0.0174	< 0.0050		0.0414	0.0912	22.300	0.2010		0.9990	2.5100		0.0470	20.938
12	0.0185			0.0414	0.0918	22.396	0.2020		1.0000	2.5143		0.0473	20.951
13	0.0200			0.0415	0.0921	22.423	0.2029		1.0000	2.5160		0.0480	20.972
14	0.0220			0.0419	0.0925	22.470	0.2080		1.0030	2.5180		0.0500	20.990
15	0.0246			0.0420	0.0940	22.471	0.2085		1.0100	2.5250		0.0510	21.000
16	0.0250			0.0420	0.0961	22.472	0.2137		1.0100	2.5360		0.0510	21.010
17				0.0431	0.1000	22.480	0.2150		1.0120	2.5700		0.0521	21.020
18					0.1000	22.520	0.2160		1.0200	2.5880		0.0577	21.022
19					0.1010	22.521	0.2220		1.0200	2.6052		0.0578	21.028
20						22.589	0.2230		1.0270	2.6125		0.0585	21.050
21						22.593	0.2240						21.188
22													
Mean	0.0166	0.0021	0.0002	0.0395	0.0916	22.316	0.2038	51.870	0.9967	2.5198	0.0106	0.0472	20.895
STDV	0.0045	0.0009	0.0000	0.0025	0.0049	0.2080	0.0115	0.1838	0.0168	0.0427	0.0009	0.0069	0.1647
Certified	0.017	0.0021	(<0.0002)	0.039	0.092	22.3	0.204	(<52)	0.997	2.52	0.0106	0.047	20.9
UCRM	0.003	0.0008		0.001	0.002	0.1	0.005		0.008	0.02	8000.0	0.003	0.08
Methods	I,IM,O,X,G	I,IM,O,X	O,I,IM	C,O,G	I,O,X,G,IM	I,O,X,G	I,O,X,G,IM		I,O,X,G	I,O,X,G	F,O	I,O,X,G,IM	I,O,X,G
	0	Р	Pb	S	Sb	Si	Sn	Ti	V	W	Z	'r	
1	0.0054	0.0220	0.0001	0.0042	0.0004	0.7930	0.0080	0.1700	0.0097	0.000	0.0	005	
2	0.0060	0.0220	0.0002	0.0044	0.0004	0.8100	0.0090	0.1700	0.0110	0.000	0.0	018	
3		0.0228	0.0002	0.0048	0.0009	0.8184	0.0097	0.1710	0.0114	0.000)9 <0.0	010	
4		0.0230	0.0006	0.0050	0.0012	0012 0.8200		0.1710	0.0120	0.003	30 < 0.0	010	
5		0.0240	0.0010	0.0050	0.0019	0.8200	0.0098	0.1722	0.0127	0.003	30 <0.	002	

3		0.0228	0.0002	0.0048	0.0009	0.8184	0.0097	0.1710	0.0114	0.0009	<0.0010
4		0.0230	0.0006	0.0050	0.0012	0.8200	0.0098	0.1710	0.0120	0.0030	<0.0010
5		0.0240	0.0010	0.0050	0.0019	0.8200	0.0098	0.1722	0.0127	0.0030	<0.002
6		0.0240	0.0010	0.0050	0.0079	0.8230	0.0102	0.1740	0.0140	0.0050	<0.002
7		0.0268	0.0040	0.0050	<0.0010	0.8240	0.0105	0.1752	0.0147	0.0050	<0.005
8		0.0268	0.0040	0.0053	<0.002	0.8319	0.0107	0.1761	0.0166	0.0050	<0.005
9		0.0268	< 0.001	0.0055	<0.005	0.8370	0.0120	0.1765	0.0204	0.0054	
10		0.0277	<0.0010	0.0058		0.8370	0.0120	0.1800	< 0.002	0.0056	
11		0.0280	<0.0020	0.0059		0.8400	0.0120	0.1800	<0.01	0.0060	
12		0.0280	<0.005	0.0060		0.8420	0.0120	0.1800		0.0120	
13		0.0300		0.0062		0.8440	0.0126	0.1820		0.0120	
14		0.0310				0.8521	<0.005	0.1820		0.0150	
15		0.0310				0.8530	<0.01	0.1823		<0.0010	
16		0.0310				0.8570		0.1840		<0.005	
17		0.0321				0.8600		0.1850		<0.01	
18		0.0331				0.8650		0.1900			
19		0.0340				0.8860					
20		0.0356				0.8923					
21		0.0370				0.8940					
22						0.9030					
Mean	0.0057	0.0284	0.0014	0.0052	0.0021	0.8456	0.0106	0.1779	0.0136	0.0056	0.0012
STDV	0.0004	0.0045	0.0017	0.0006	0.0029	0.0290	0.0014	0.0058	0.0033	0.0045	0.0009
Certified	(<0.006)	0.028	(0.001)	0.0052	0.002	0.85	0.0106	0.178	0.014	(0.006)	(<0.001)
UCRM		0.002		0.0008	0.003	0.01	8000.0	0.003	0.003		
Methods	F	I,O,X,G,IM	I,IM,O,X	C,I	IM,O,I,X	I,O,W,X,G	I,IM,O,X	I,O,X,G,IM	I,IM,O,X,G	I,IM,O,X	I,O,IM,X

Legend: W = Classical, C = Combustion, F = Fusion, A = AA or GFAA, I = ICP or DCP, IM=ICP-MS, D = DC Arc, O = AES, X = XRF, G = GDAES or GDMS, H = Hollow Cathode AES

